

The Amray Model 3600 LEAP (Low Energy Advanced Performance) can propel your field emission SEM

(Low Energy Advanced Performance) can propel your field emission SEM performance beyond current boundaries to a new standard of excellence. The Amray 3600 LEAP delivers: □ high resolution − 4nm at 1kV, 1.5nm at 15kV □ optimized geometry for □ a short working distance at high tilts

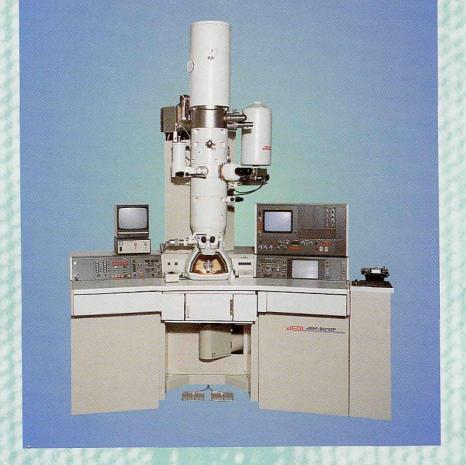
with large samples (6mm w.d. at 45° tilt) □ high kV (25kV) for uncompromised analytical capabilities □ highly reliable patented Schottky field emission gun □ 2048 x 2048 frame buffer for advanced digital imaging □ two 17", high resolution, 1000 line viewing monitors □ 5 axes motor-



ized eucentric stage □ motorized 8" linear load lock for rapid sample exchange □ embedded computer control for all SEM functions

The Amray 3600 LEAP provides resolution that's out of this world – call 1-800-225-1462 for complete information on the Model 3600 LEAP and other Amray systems.





Sights Unseen.

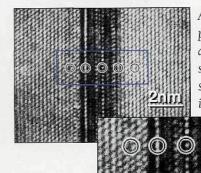
With the New JEM-2010F Field Emission Electron Microscope You'll See It ... If It's There.

From JEOL....the newest generation of precision equipment that permits unprecedented resolution in 3-dimensional, subnanometer analysis of microstructures.

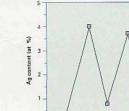
Featuring user-friendly operation and long-term stability, the JEM-2010F also offers:

- Schottky Emission: High Current High Brightness
- High Probe Current: 0.5nm Probe with 100 pA Current
- High Resolution: Information Limit 1.4Å, Scherzer 1.9Å
- Holography: Option Available
- STEM Resolution: 0.2nm Magnification: 8MX

Discover the JEM-2010F and visit sights previously unseen.



Al-Cu-Mg (Ag) precipitate in aluminum showing silver segregation to interface.



Data courtesy of Dr. James M. Howe, Department of Materials Science & Engineering, University of Virginia, U.S.A.



JEOL USA, Inc., 11 Dearborn Road, Peabody, MA 01960 Tel: 508-535-5900 Fax: 508-536-2205 e-mail: eod@jeol.com